Record of Letter Ballot Review by TC Chapter for Procedural Review

Region/Locale: Japan

Global Technical Committee: Silicon Wafer

TC Chapter Cochairs: Tetsuya Nakai (SUMCO), Ryuji Takeda (GlobalWafers Japan)

Standards Staff: Mami Nakajo

	Scheduled in Background Statement	Actual
Date	December 14, 2022	December 14, 2022
Location	Tokyo Big Sight [Hybrid]	Tokyo Big Sight [Hybrid]
Reason for Change of Date and/or Location (if changed)		

Note: See Regulations ¶ 9.5 Exceptions for allowable reason to change.

I. Document Number and Title

	Document Title
6860	Revision of SEMI M41-0615, Specification of Silicon-
	on-Insulator (SOI) for Power Device/ICs

II. Tally

Standards staff to fill in.

Voting Tally: As-cast tally after close of voting period

Note: A minimum of 60% of the Voting Interests that have TC Members within the global technical committee that issued the Letter Ballot must return Votes. (*Regulations* ¶ 9.6.2.1.1)

Voting Tally:

Returned Votes		Distribution		Return Rate	
66	ŀ	110	=	60.0%	≥60%
41					
0		Total	Vote	rs with Rejects	0
43					
	0	66 ÷	66 ÷ 110 41 0 Total	66 ÷ 110 = 41 0 Total Vote:	66 ÷ 110 = 60.0% 41 0 Total Voters with Rejects

Note: See Regulations § 3.2.1 for definition of Voting Interest.

III. Rejects

None

IV. Other Technical Issues

None

V. Comments

V- (i) Voters' Comments
Commenter 1 (Moudghil, Ashish Saurabh / Lam Research) - Comment 1

n <u>me</u>	ente	r 1 (<mark>Moudg</mark>	hil, Ashish Saurabh / Lam Research) - Comment 1									
Com	*TF	/TC Chapter	to fill in section/paragraph #, if necessary.									
Comment	plea											
	The	e TC Chapter agreed to do one of the following actions.										
	*No	No motion is required in this step.										
Δc		Already add	ressed by Commenter #, Comment #									
Action	x No further action was taken by the TC Chapter.											
			TF for more consideration.									
		New Busine										
		Editorial Ch										
		Options	Case 1: No vote in this section:									
		for editorial	To be included and voted on as a group in § VI. Editorial Changes Other than Those Voted on in § V.									
		change	Case 2: Voted in this section:									
		(check one)	Original section number and at least one full sentence are required in "FROM" and "TO" fields.									
		FROM: Section/Paragraph xxx										
Ed	1	TO: Section/Paragraph xxx										
itorial (Justification	on (If necessary)									
Editorial Changes		FROM: Sec	FROM: Section/Paragraph xxx									
ľ	2	TO: Sectio	n/Paragraph xxx									
		Justification	n (If necessary)									
M	otion	1	To approve above editorial change(s)									
М	otion	by/2 nd by	Name (Company)/Name (Company)									
Di	iscus	ssion	XXXX									
V	ote		XX Y-XX N; Motion passed/failed.									

Commenter 2 (Hartsough, Larry /UA Associates) - Comment 1

editorial change (check change) Case 2: Voted in this section:	n <u>me</u>	ente	r 2 (Hartso	ugh, Larry /UA Associates) - Comment 1									
The TC Chapter agreed to do one of the following actions. "No motion is required in this step. Already addressed by Commenter #, Comment # No further action was taken by the TC Chapter. Refer to the TF for more consideration. New Business x Editorial Change Options for editorial change (check one) Case 1: No vote in this section: To be included and voted on as a group in § VI. Editorial Change (check one) To be included and voted on in § V. Case 2: Voted in this section: Original section number and at least one full sentence are required. FROM: 3. Referenced Standards and Documents 3.1 SEMI Standards and Safety Guidelines SEMI MF26 — Test Methods for Determining the Orientation of a Semiconductive Single Comments SEMI MF43 — Test Methods for Resistivity of Semiconductor Materials TO: 3. Referenced Standards and Documents 3.1 SEMI Standards and Safety Guidelines SEMI MF45 — Test Methods for Conductivity Type of Extrinsic Semiconducting Materials SEMI MF46 — Test Methods for Determining the Orientation of a Semiconductive Single Comments SEMI MF47 — Test Methods for Conductivity Type of Extrinsic Semiconductive Single Comments TO: 3. Referenced Standards and Documents 3.1 SEMI Standards and Safety Guidelines SEMI MF46 — Test Methods for Conductivity Type of Extrinsic Semiconductive Single Comments To: 3. Referenced Standards and Safety Guidelines FROM: Section/Paragraph xxx TO: Section/Paragraph xxx	Com	*TF	/TC Chapter to fill in section/paragraph #, if necessary.										
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2 TO: Section/Paragraph xxx			· · · · · · · · · · · · · · · · · · ·										
Justification (If necessary)		2											
			Justification	on (If necessary)									
Motion To approve above editorial change(s)	M	otion	1	To approve above editorial change(s)									

Motion by/2 nd by Gerd Pfeiffer (Soitec)/ Masanori Yoshise (SELF)						
Discussion	None					
Vote	8 Y-0 N; Motion passed					

V-(ii) Comments Created by Handling Negative None

VI. Editorial Changes Other than Those Voted on in § V

Original section/paragraph number and at least one full sentence are required in "FROM" and "TO" fields.

None

VII. Approval Conditions Check

VII. - (i). Approval Rate

APPROVAL CONDITION 1: All Negatives have been discussed and were withdrawn, found not related, found not persuasive, or addressed by a technical change. (*Regulations* ¶ 9.6.2.1.2)

APPROVAL CONDITION 2: At least 90% of the sum of valid Voting Interest Accept and Voting Interest Reject Votes must be Accept. (*Regulations* ¶ 9.6.2.1.3)

Note: If both approval conditions are not satisfied, the Document fails.

		Accepts		(Accepts + Valid Rejects)			
Approval Rate	=	43	/	43	=	100.0%	≥90%

VII. – (ii) Approval Level (check one)

Note: See Regulations § 9.6.2 for further information.



Globally Approved (No Ratification Ballot needed):
The Letter Ballot meets the Letter Ballot approval conditions for the global technical committee.



The Letter Ballot meets the Letter Ballot approval conditions for the TC Chapter and a Ratification Ballot will be issued to validate technical changes.

VIII. Safety Check

Note: See Regulations § 15 for further information.

	X	Th is	is is not a s still technica	not a Safety Document, when all safety-related information is removed, the Document chnically sound and complete. (<i>Regulations</i> ¶ 8.7.1)						
Motion				is a Safety Document, when all safety-related information is removed, the Document is not lically sound and complete. (Regulations ¶ 8.7.2)						
				Safety Checklist (<i>Regulations</i> ¶ 15.3) is complete and has been included with the Document throughout the balloting process. (<i>Regulations</i> ¶ 15.1.2)						
	Motion by/2 nd by			Gerd Pfeiffer (Soitec)/ Masanori Yoshise (SELF)						
Discussion None										
	Vote 8-0									

IX. Intellectual Property (IP) Check

Note: This Letter Ballot may cover all or part of a Standard or Safety Guideline. Regardless of the coverage, this IP check applies to the entire Standard or Safety Guideline*. See *Regulations* § 16 for further information.

Х	The TC Chapter meeting chair asked those participating, if they were aware of any patented technology that might be relevant (see <i>Regulations</i> ¶ 16.3.1.1) to the Standard or Safety Guideline; or, any copyrighted items or trademarks that are used/reproduced (see <i>Regulations</i> ¶ 16.4.1.2) in the Standard or Safety Guideline. (Also see, <i>Regulations</i> § 8.8)							
	X	The question is NOT answered in affirmative (No potentially material patented technology or use/reproduction of copyrighted items/trademarks is known.)	GO TO SECTION X.					
		The question is answered in affirmative	Is any of the known IPs a patented		Yes, at least one of them is a patented technology	GO TO IX (a) "Patented Technology" subsection		
			technology?		No	GO TO IX (b) "Copyright items" subsection		

IX(a) Patented Technologies subsection IX(a1) Total numbers of Patented Technologies to be dealt with

# Fill	(i) ittiowii i atolitoa	Fill	technologies first became known to the TC Chapter on or after the day	Postpone assessment of such patented technologies to be performed at the next scheduled TC Chapter meeting.
number th	the Standard/Safety Guideline	# Fill	(n) Number of patented technologies first became known to the TC Chapter before the day of the issuance of this Letter Ballot	GO TO IX (a2)

IX(a2) Assessment of disclosed patented technologies

Disclosed patented technology #1 (Brief description, e.g., patent title and number):			Date of Assessment (If different from the date of Letter Ballot adjudication) MM/DD/YYYY				
Is disclosed patented			Is the us	se of this	YES PROCEED to asses NEXT one, or if this is the last of GO TO IX(a3)		
technology #1 found to be "might be material" to the Standard/Safety Guideline?			justified?			NO	The Document is failed and returned to the TF
		NO	No furth	er action is nee	ded	for patente	ed technology #1

This table is needed for each disclosed patented technology.

IX(a3) LOA status check of PMPT of which inclusion assessed to be justified

LOA Status of PMPT #1								
		YES		EXT one, e, GO TO IX(b)				
Has an LOA for this patented technology		NO	JM		Ask ISC for spe	ecial permission to publish.		
been received from every owner?			MOTION		Quit activity.	The Document is failed and returned to the TF		
					Wait for LOA	PROCEED to check NEXT one, or if this is the last one, GO TO IX(b1)		
			Mot	tion	by/ 2 nd by	Name (Company)/Name (Company)		
				cuss	sion	XXXX		
				е		XX Y-XX N; Motion passed (or failed)		

This table is needed for each PMPT of which inclusion assessed to be justified.

IX(b1) Total numbers of copyrighted items to be dealt with

r Fill number	(o) Known copyrighted items that are used or	o > 0 There is at least one known copy righted items that might be relevant to the	GO TO IX (b2)
number	reproduced to the	Standard/Safety Guideline	

Standard/Safety Guideline		o = 0 There is no disclosed copyrighted item	GO TO IX (c)
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IX(b2) Assessment of disclosed copyrighted items

Disclosed copyrighted item #1 (Brief description of its use in the Document):								
Is disclosed copyrighted		YES	Is the use/reproduction of this copyrighted item technically justified?		YES	PROCEED to assess NEXT one, or if this is the last one, GO TO IX(b3)		
item #1 used or reproduced in the Standard/Safety Guideline?					NO	The Document is failed and returned to the TF		
		NO	No further action is needed for copyrighted item #1					

This table is needed for each disclosed copyrighted item.

IX(b3) Copyright release status check of copyrighted item of which inclusion assessed to be justified

Copyright release Status of copyrighted item #1							
		YES	PROCEED to assess NEXT one, or if this is the last one, GO TO IX(c)				
Has the copyright		NO	MOTION		Ask ISC for special permission to publish.		
release been received from its owner?.					Quit activity.	The Document is failed and returned to the TF	
					Wait for copyright release letter	PROCEED to check NEXT one, or if this is the last one, GO TO IX(c)	
					by/ 2 nd by	Name (Company)/Name (Company)	
				cuss	sion	XXXX	
				е		XX Y-XX N; Motion passed (or failed)	

This table is needed for each copyrighted item of which use/reproduction assessed to be justified.

IX(c) Assessment of disclosed (identified) trademark

	YES	Is every instance of trademark use technically justified?		YES	GO TO IX(d)	
Is there any trademark in the Standard/Safety Guideline?				NO	The Document is failed and returned to the TF	
	NO	GO TO IX(d)				

IX(d) IP check completion condition check

The co-chair checks if any Patented Technologies first become known to		YES	Sections IX(a2) and IX(a3) shall be completed and recorded for such patented technologies at next scheduled meeting of the TC Chapter. Until then, the
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the TC Chapter on or after the day of the issuance of this Letter Ballot? i.e., m>0 in IX(a1)		TC Chapter shall NOT go to X (making motion to pass/fail this Document) (see Regulations ¶ 16.4.1.2) Until then this Letter Ballot Review is on hold.
	NO	GO TO X

X. Action for This Document

			ment passed TC Chapter review as balloted and will be forwarded to the ISC A&R cedural review.										
M	X		ment passed TC Chapter review with editorial changes and will be forwarded to test for procedural review.										
Motion		editorial ch	his Document passed TC Chapter review with technical changes and with or without ditorial changes and will be forwarded to the ISC A&R SC for procedural review. A atification Ballot will be issued to verify the technical changes.										
		This Docu	This Document failed TC Chapter review and will be returned to the TF for rework.										
	This Document failed TC Chapter review and work will be discontinued.												
I		on by/ ^d by	Ge	erd Pfeiffer (Soitec)/ Masanori Yoshise (SELF)									
Discussion			None										
	٧	ote											
F	inal	Action	9	Motion passed									
Final Action			Motion failed										

Note: If the use of PMPT or copyrighted item is justified by the TC Chapter, LOA or release form must be received before publication can proceed.